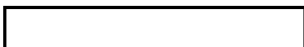


IAS/TA - 59/68
27 November 1968

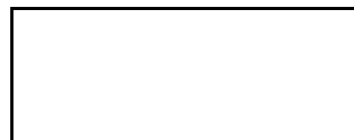
MEMORANDUM FOR: Chief, Development and Engineering Division, TSSG/NPIC

ATTENTION :



SUBJECT : Installation of Prototype Twin-Stage PI Comparator

We have, as you know, been following this R&D project with interest and look forward to arrival of the prototype about August 1969. We would be pleased to have the prototype installed in IAS for evaluation and ultimate production use. If this meets with your approval, please advise as to the electrical and environmental requirements of the device in order that we may initiate site preparations.



Technical Advisor
Imagery Analysis Service

DISTRIBUTION

Original & 1 - Addressee
1 - TA/IAS

NGA Review Complete

SECRET

(When Filled In)

SPEED LETTER	REPLY REQUESTED		DATE
	YES	<input checked="" type="checkbox"/>	NO
TO : Ch/Plans, Budget & Equipment Staff/IEG		FROM:	
ATTN: 			

In accordance with our discussions of today, it is understood that it is IEG's position that the prototype Twin-State, On-Line PI Comparator should not be installed in their spaces and it is, therefore, acceptable to install it in IAS/CIA with the understanding that it will be available to IEG for the evaluation purpose of determining whether IEG desires to purchase production versions of this instrument. If either of these understandings are in error, please advise as soon as possible.

SIGNATURE

REPLY	DATE
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SIGNATURE

RESPONDER'S FILE

SECRET

02227

IPO/OSB/M-187-66
27 December 1966

MEMORANDUM FOR: Assistant for Technical Development, NPIC

ATTENTION:

[REDACTED]

SUBJECT: Twin-Stage On-Line PI Comparator

[REDACTED]

requirements for this instrument from both IAD and PAG.

2. The Twin-Stage On-Line comparator is unable to fill any known Photographic Analysis Group requirement that is not presently being satisfied by use of some of the equipment described below. PAG photo interpreters have access to the Chip Comparators and the [REDACTED] Reader-Viewer which have on-line capabilities. Normally the measurements published in our PI reports are furnished to PAG by TID. Comparative measurements are made by the PI for his own use and as a rough check on the TID measurements furnished to him. These PI measurements may be made by a variety of instruments such as the Projected Scale Micrometer, [REDACTED] Measuring Macroscopic, Glass Plate grids and eventually the Filar Eyepiece.

3. Although the Photographic Analysis Group does not have a requirement for the subject item, we would be interested in being informed of any further developments that concern this instrument.

[REDACTED]

Colonel, USA

Assistant for Photographic Analysis, NPIC

Distribution:

Orig & 1 - Addressee

1 - [REDACTED]

1 - Info [REDACTED]

1 - Asst. for PA

1 - Chrono